TOSHIBA Transistor Silicon PNP Epitaxial Type (PCT process)

# 2SA1314

## Strobe Flash Applications Audio Power Applications

• High DC current gain and excellent linearity

$$h_{FE}(1) = 140 \text{ to } 600 \text{ (V}_{CE} = -1 \text{ V}, I_{C} = -0.5 \text{ A})$$

: hFE (2) = 60 (min), 120 (typ.), (VCE = 
$$-1$$
 V, IC =  $-4$  A)

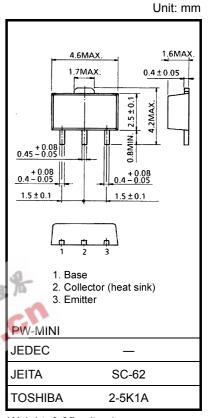
· Low saturation voltage

$$: V_{CE (sat)} = -0.5 \text{ V (max) (IC} = -2 \text{ A, IB} = -50 \text{ mA)}$$

- · Small package
- Complementary to 2SC2982

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		$V_{CBO}$	-20	V	
Collector-emitter voltage		V <sub>CEO</sub>	-10	V	
Emitter-base voltage		V <sub>EBO</sub>	-6	V	
Collector current	DC	IC	-2	-0	
	Pulsed (Note 1)	I <sub>CP</sub>	-4	A	
Base current		IB	-2	Α	
Collector power dissipation		PC	500	mW	
		P <sub>C</sub> (Note 2)	1000		
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	−55 to 150	°C	



Weight: 0.05 g (typ.)

- Note 1: Pulse test: pulse width = 10 mS (max), duty cycle = 30% (max)
- Note 2: Mounted on a ceramic substrate (250 mm<sup>2</sup> × 0.8 t)
- Note 3: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

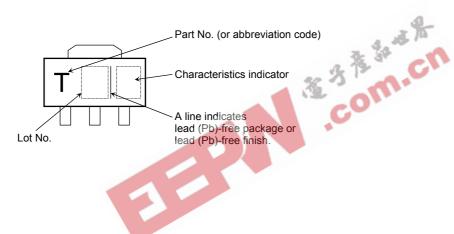
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

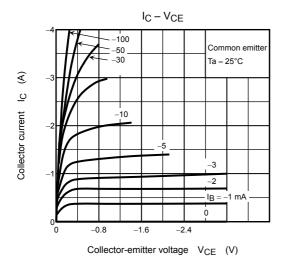
### **Electrical Characteristics (Ta = 25°C)**

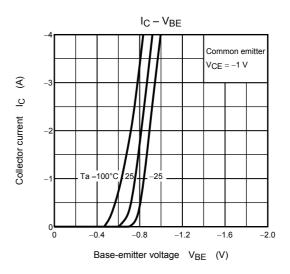
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> = -20 V, I <sub>E</sub> = 0	_	_	-100	nA
Emitter cut-off current	I <sub>EBO</sub>	$V_{EB} = -6 \text{ V}, I_{C} = 0$	_	_	-100	nA
Collector-emitter breakdown voltage	V (BR) CEO	$I_C = -10 \text{ mA}, I_B = 0$	-10	_	_	V
Emitter-base breakdown voltage	V (BR) EBO	$I_E = -1 \text{ mA}, I_C = 0$	-6	_	_	V
DC current gain	h <sub>FE (1)</sub> (Note 4)	V <sub>CE</sub> = -1 V, I <sub>C</sub> = -0.5 A	140	_	600	
	h <sub>FE</sub> (2)	V <sub>CE</sub> = -1 V, I <sub>C</sub> = -4 A	60	120	_	
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	I <sub>C</sub> = -2 A, I <sub>B</sub> = -50 mA	_	-0.2	-0.5	V
Base-emitter voltage	V <sub>BE</sub>	V <sub>CE</sub> = -1 V, I <sub>C</sub> = -2 A	_	-0.83	-1.5	V
Transition frequency	f <sub>T</sub>	V <sub>CE</sub> = -1 V, I <sub>C</sub> = -0.5 A	_	140	_	MHz
Collector output capacitance	C <sub>ob</sub>	V <sub>CB</sub> = -10 V, I <sub>E</sub> = 0, f = 1 MHz	_	50	1	pF

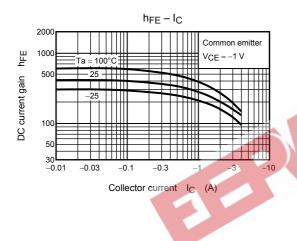
Note 4:  $h_{FE\ (1)}$  classification A: 140 to 280, B: 200 to 400, C: 300 to 600

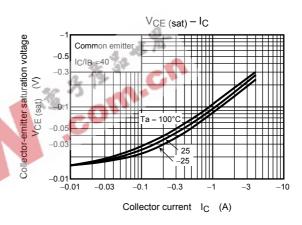
#### Marking

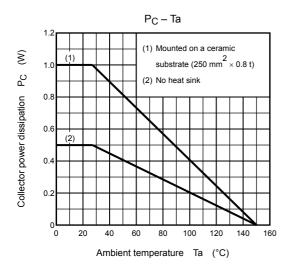


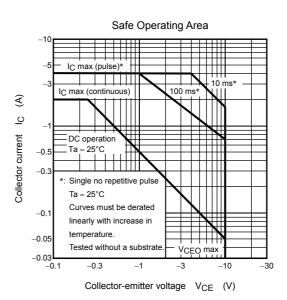












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